Search Notes			
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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/659,101	CHAN ET AL.	
Examiner	Art Unit	
Randall Chin	1744	

	SEARCHED		
Class	Subclass	Date	Examiner
15	143.1	1	1
15	167.1	8/1/2005	RC
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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	DATE	EXMR
Inventor name search	8/1/2005	RC
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